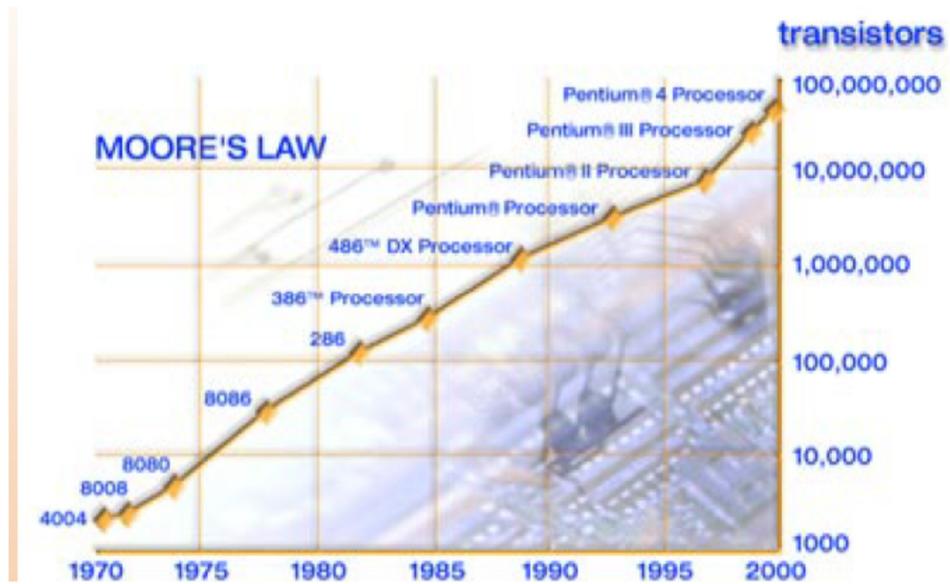
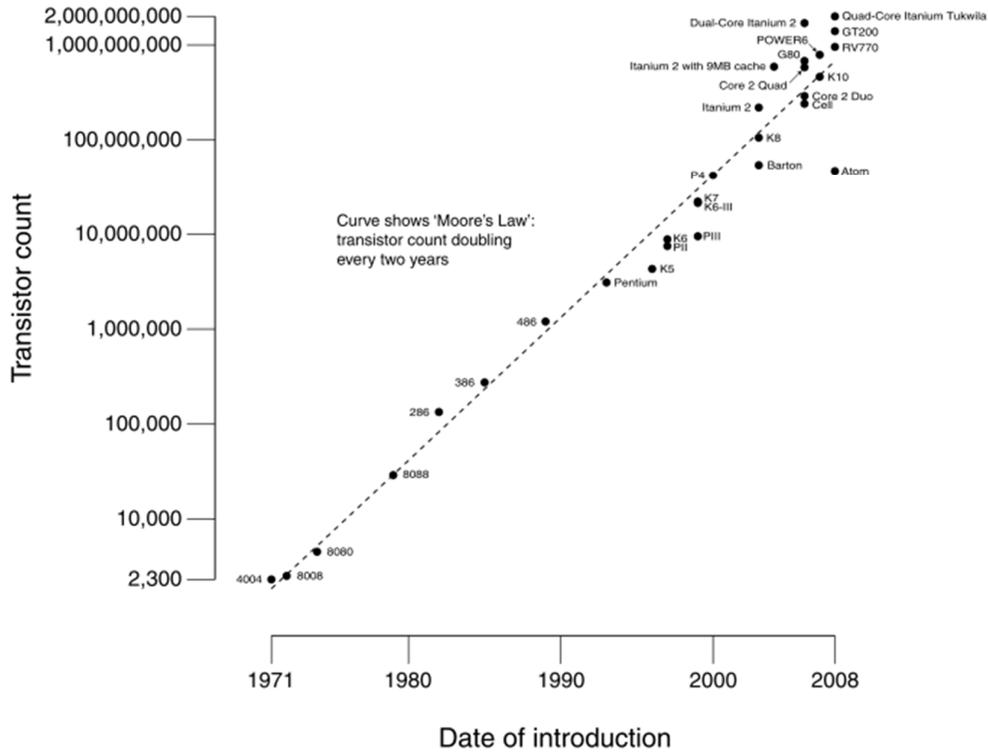
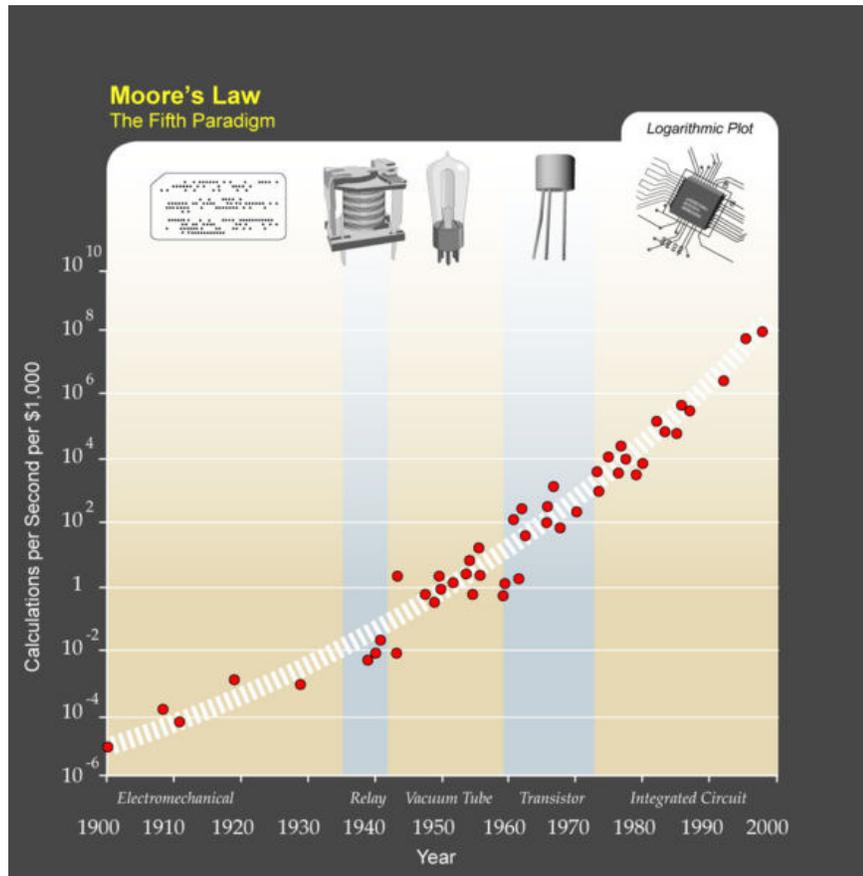


Sviluppo tecnologico dell'elettronica digitale:

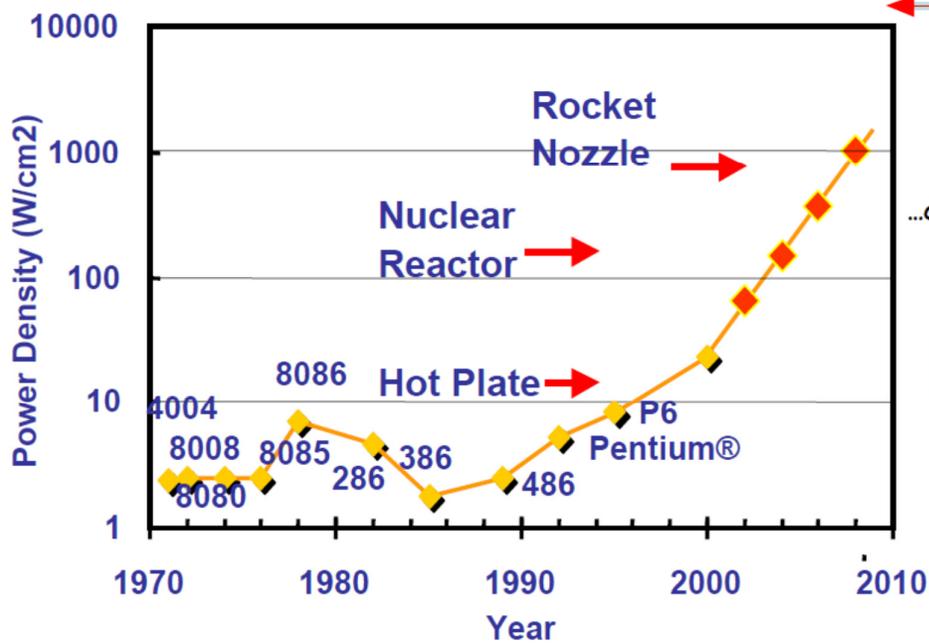
CPU Transistor Counts 1971-2008 & Moore's Law



Prestazioni e problemi:

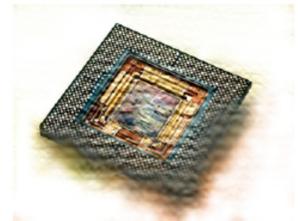


Power Density



Sun's Surface

...chips might become hot...



Famiglia logica:

Insieme di gates che svolgono le funzioni logiche elementari
basata su prefissati livelli logici (tensione/corrente), tecnologia (BJT/MOS),
tempi di commutazione, capacita' di interconnessione (pilotaggio/bus/...), etc
→ Insieme di circuiti integrati direttamente interconnettibili

Inizio '900: Rele'

(es. centralini telefonici, Z3 (Germania - 1941))

Anni '40-'50: Tubi a vuoto

(es. ENIAC (US - 1946))

Anni '60: Transistor bipolari

(Discreti, poi integrati - Es. RTL, DTL, TTL,...)

Anni '70 - '80: PMOS, NMOS

(Zilog Z80, Intel 8080, Motorola 6502, Fairchild F8, ..)

Anni '90 → : CMOS

~ Tutto!

Proprieta' fondamentale di ogni famiglia logica:

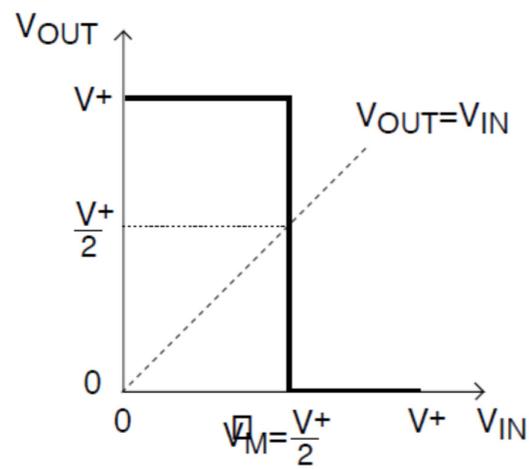
Tutti tipi di gate basati su un'unica funzione logica fondamentale: NOT

Circuito che esegue la funzione logica NOT: Inverter

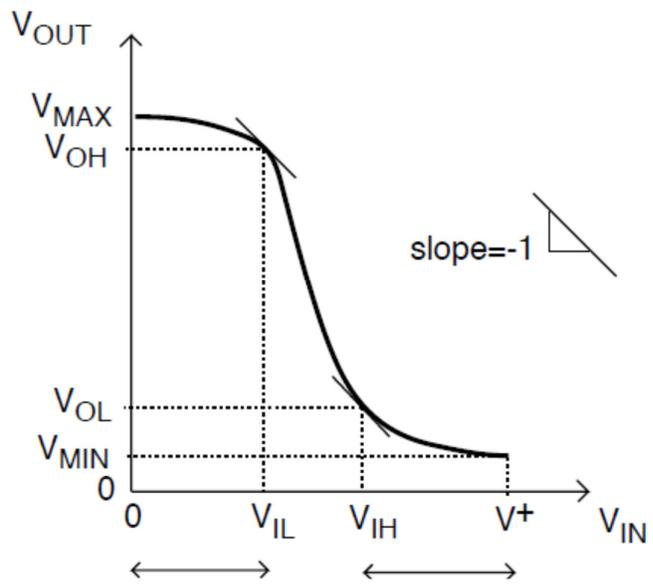
→ Inverter come mattone fondamentale

Caratteristica di trasferimento: Inverter ideale

V_M : tensione per cui $V_{in} = V_{out}$



Caratteristica di trasferimento: Inverter reale



Intervallo di V_{in}

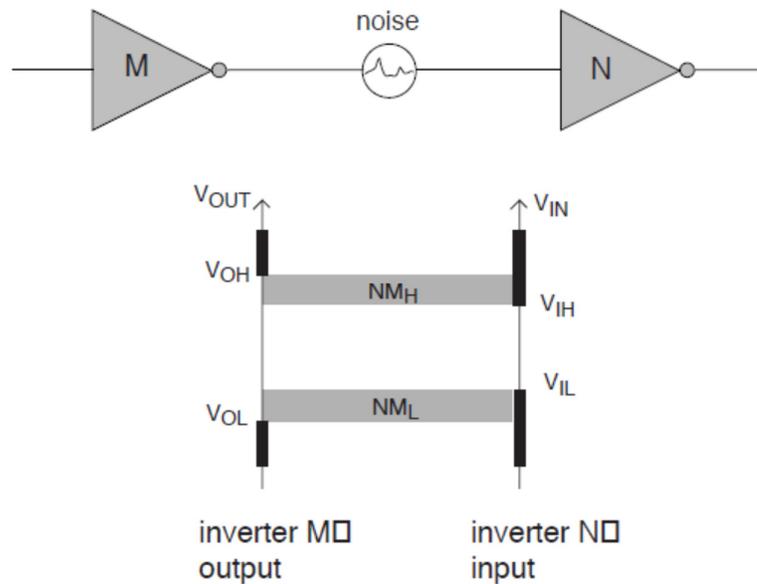
Intervallo di V_{in}

che da' $V_{out} = 1$

che da' $V_{out} = 0$

V_{IL}, V_{IH} : Livelli di ingresso min, max per i quali
la pendenza della curva di trasferimento = -1

V_{OL}, V_{OH} : Livelli di uscita min, max per i quali
la pendenza della curva di trasferimento = -1



Condizioni in figura: M pilota correttamente N

Margine di rumore:

$V_{OH} - V_{IH}$ mdr 'alto'

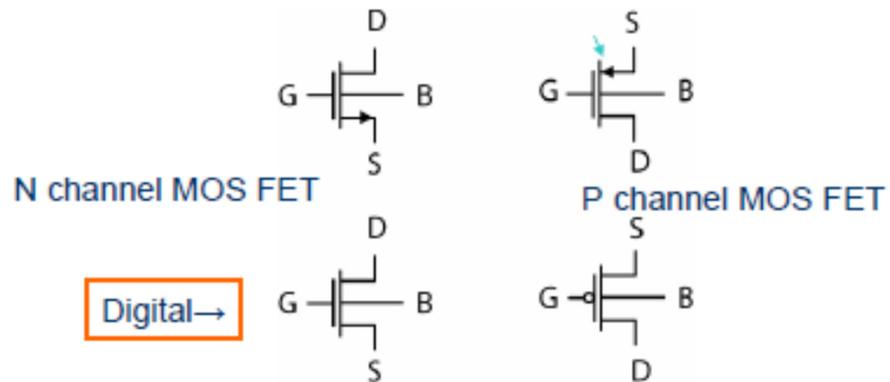
$V_{IL} - V_{OL}$ mdr 'basso'

→ Margine di rumore elevato = Garanzia di funzionamento corretto

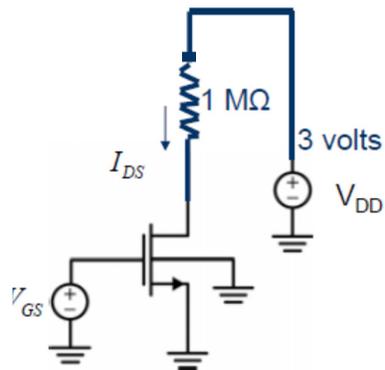
MOS usati come interruttori:

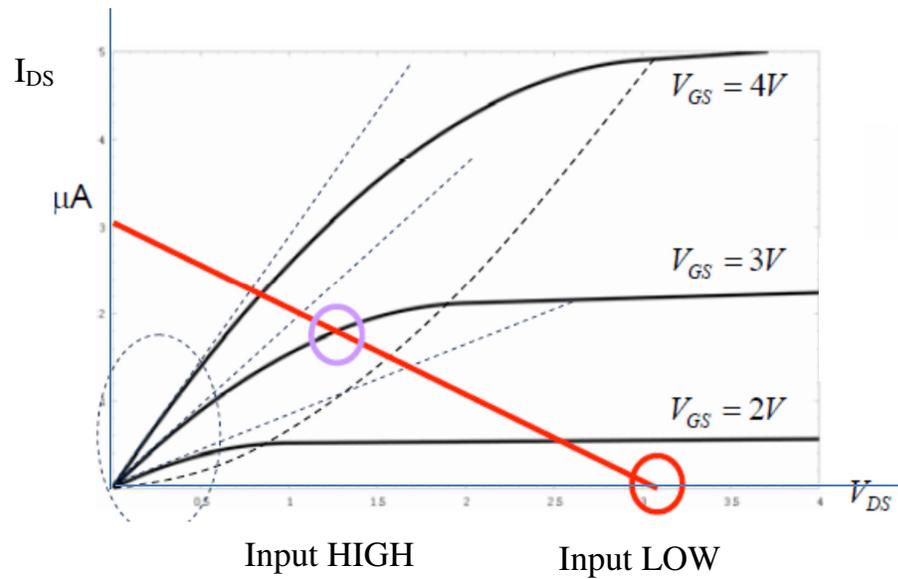
NMOS ON per $V_G +v_a$

PMOS ON per $V_G -v_a$



Inverter NMOS:





Problemi inverter NMOS/PMOS:

→ Per input *HIGH*, output $\sim 1.2V$

→ Stadio successivo pilotato da un *LOW* troppo alto

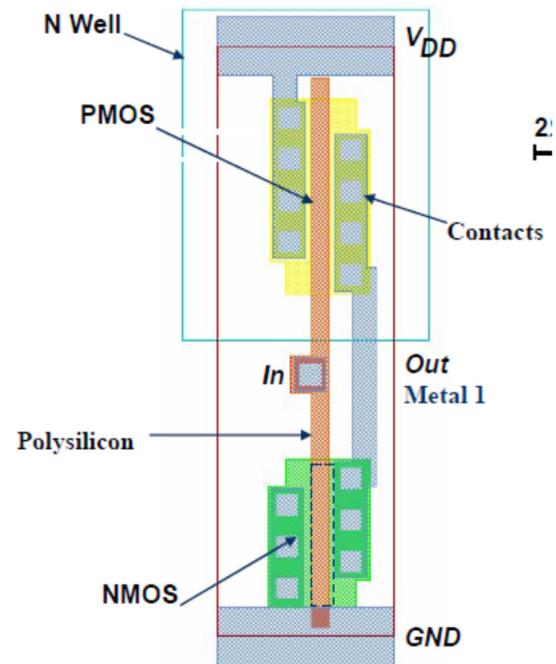
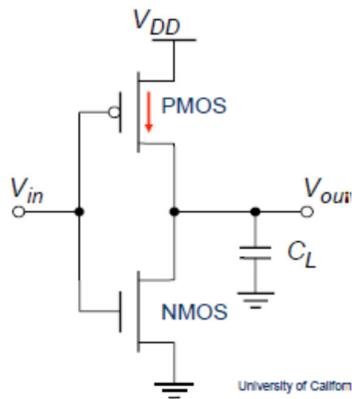
Inoltre:

R grandi: difficili e non benvenute

$I_{LOW} \sim 3\mu A \rightarrow P_{inv} \sim 10\mu W \rightarrow P_{tot} \sim 1 W / 10^5 transistor$

(1 CPU di oggi $\sim 10kW$!)

Inverter CMOS:



Caratteristica principale:

Staticamente, corrente nulla \rightarrow Consumo statico ~ 0

Lunghezza del gate = Lunghezza del canale

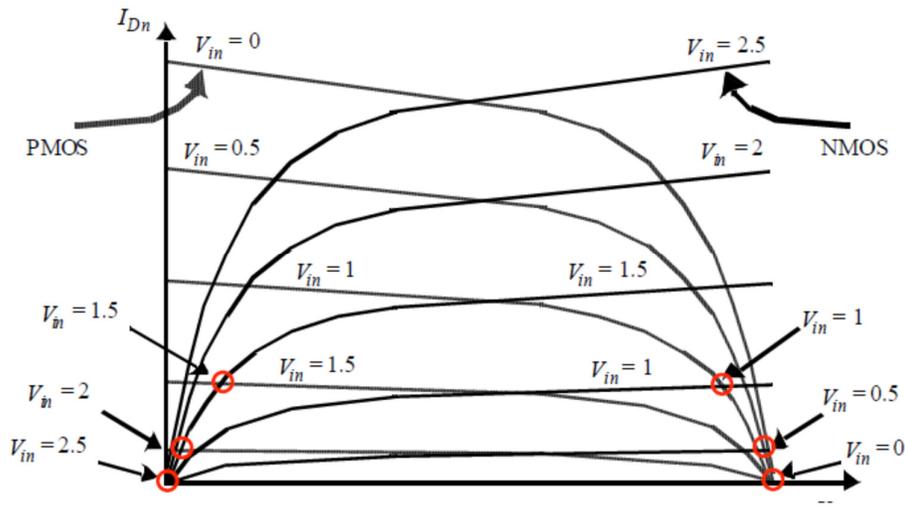
Uguale per NMOS e PMOS

Larghezza del gate = Larghezza del canale

Diversa per NMOS e PMOS,
per avere stessa corrente di drain in presenza di diverse mobilita'
per elettroni e lacune

Caratteristiche di uscita per NMOS e PMOS:

Corrente di drain (N) vs tensione fra drain e source



Valori di corrente vs tensione NMOS/PMOS per diversi V_{in}

Circoletti rossi: V_{out} = Tensione comune di NMOS e PMOS

→ Ricostruzione della relazione V_{out} vs. V_{in}

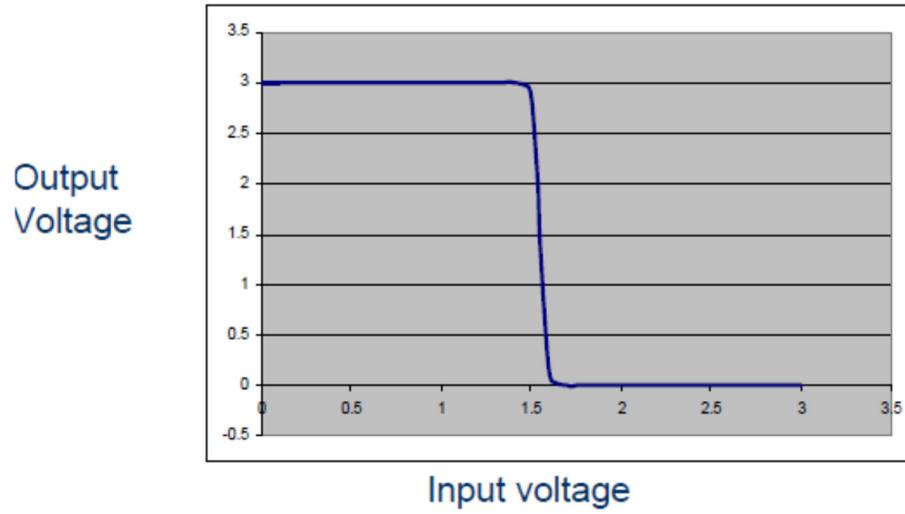
$$V_{in} = \begin{cases} 0 \\ V_{DD} \end{cases} \rightarrow V_{out} = \begin{cases} V_{DD} \\ 0 \end{cases} \text{ OK}$$

Inoltre: $V_{in} \lesssim V_{DD} \rightarrow V_{out} \gtrsim 0$, $V_{in} \gtrsim 0 \rightarrow V_{out} \lesssim V_{DD}$

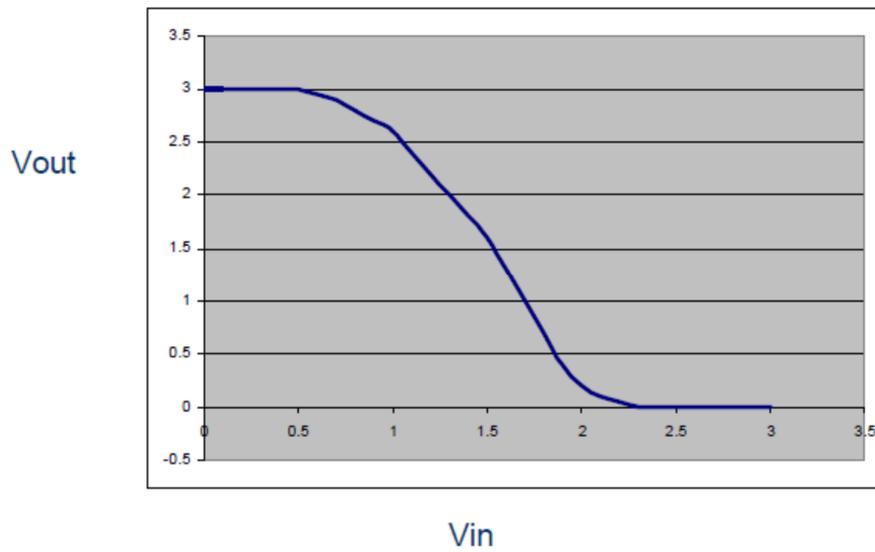
Ossia: $V_{out} \sim$ invariata per $V_{in} \neq$ da valori nominali

→ 'Margine di rumore' elevato OK

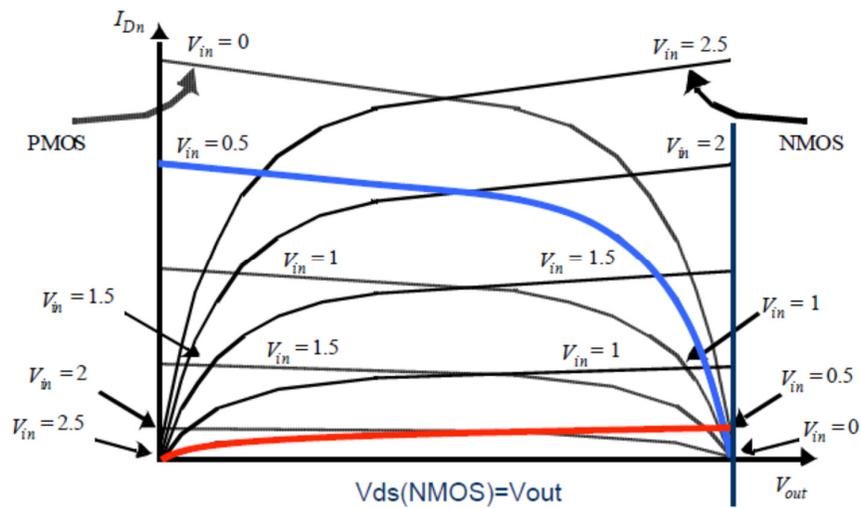
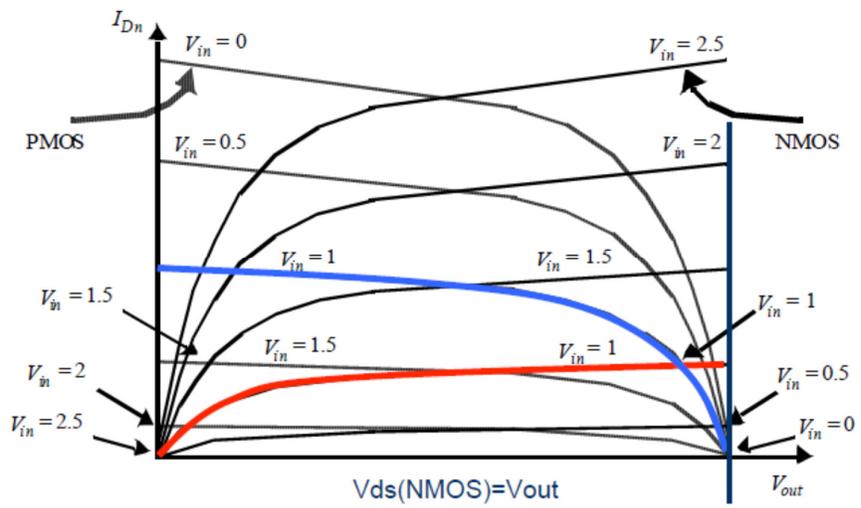
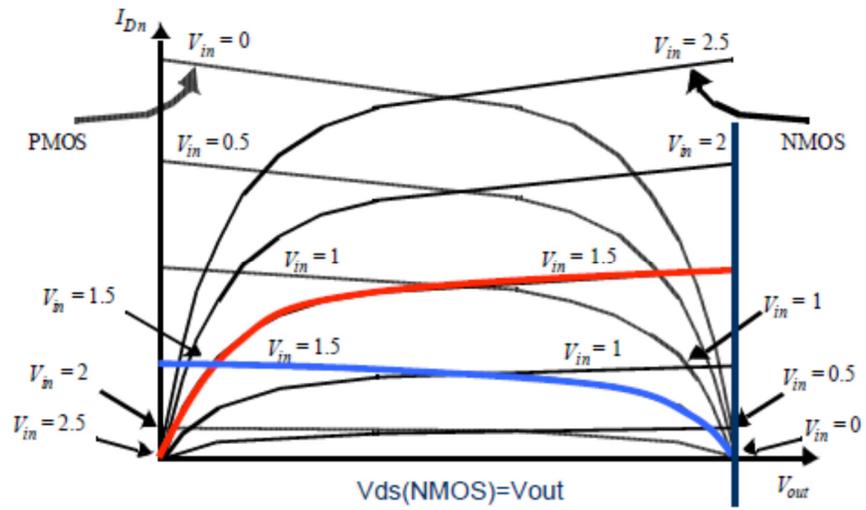
Risposta in/out di un inverter 'ideale':



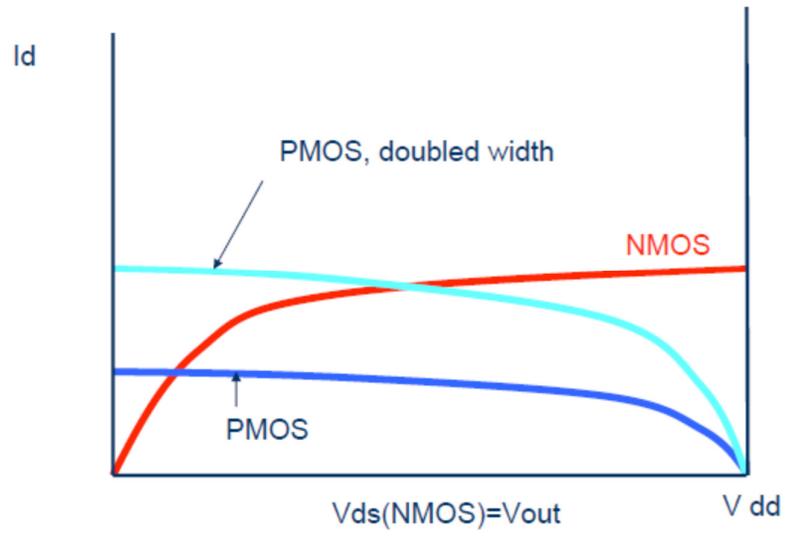
Risposta in/out di un inverter CMOS:



Infatti:



Caratteristiche di uscita per NMOS e PMOS:
fattore ~ 2 in larghezza canale garantisce simmetria



V_M tensione di drain (comune) t.c. $V_{in} = V_{out}$

Corrente per NMOS

$$I_{Dn} = v_{sat,n} W_n C_{0x} (V_M - V_{Tn})^2 (1 + \lambda_n V_M)$$

Corrente per PMOS

$$I_{Dp} = -I_{Dn} = v_{sat,p} W_p C_{0x} (V_{DD} - V_M + V_{Tp})^2 (1 + \lambda_p (V_{DD} - V_M))$$

$$g_n = v_{sat,n} W_n C_{0x}$$

$$g_p = v_{sat,p} W_p C_{0x}$$

Trascurando i λ :

$$v_{sat,p} W_p C_{0x} (V_{DD} - V_M + V_{Tp})^2 \approx v_{sat,n} W_n C_{0x} (V_M - V_{Tn})^2$$

$$\rightarrow g_p (V_{DD} - V_M + V_{Tp})^2 \approx g_n (V_M - V_{Tn})^2$$

$$\rightarrow V_{DD} - V_M + V_{Tp} \approx \sqrt{\frac{g_n}{g_p}} (V_M - V_{Tn})$$

$$\rightarrow V_M \left(1 + \sqrt{\frac{g_n}{g_p}} \right) \approx \sqrt{\frac{g_n}{g_p}} V_{Tn} + V_{Tp} + V_{DD}$$

$$\rightarrow V_M \approx \frac{\sqrt{\frac{g_p}{g_n}} (V_{DD} + V_{Tp}) + V_{Tn}}{1 + \sqrt{\frac{g_p}{g_n}}}$$

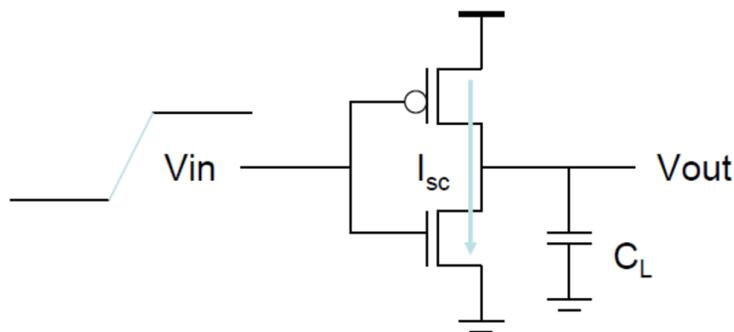
Nessuna potenza dissipata staticamente

Ma: potenza dissipata *dinamicamente*

→ Durante le transizioni

→ Carica e scarica del carico capacitivo

(← C_{out} (stadio n) + C_{in} (stadio $n+1$))



$$i_L = C_L \frac{dv_O}{dt} \text{ corrente nella capacita'}$$

$$P_P = i_L V_{DS} = i_L (V_{DD} - V_O) \text{ Pot. istantanea dissipata dal PMOS}$$

$$E_P = \int_0^{\infty} P_P(t) dt = \int_0^{\infty} C_L (V_{DD} - V_O) \frac{dv_O}{dt} dt \text{ Energia}$$

$$\rightarrow E_P = \int_0^{V_{DD}} C_L (V_{DD} - V_O) dv_O = C_L V_{DD}^2 - \frac{1}{2} C_L V_{DD}^2 = \frac{1}{2} C_L V_{DD}^2$$

$$\rightarrow E_N = \frac{1}{2} C_L V_{DD}^2 \text{ En. dissipata nel NMOS}$$

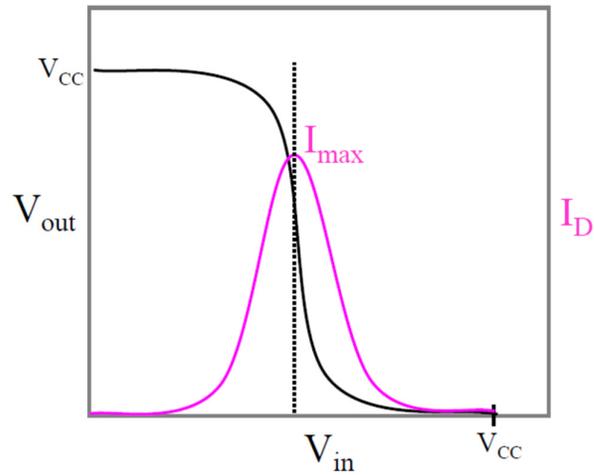
$$\rightarrow E_T = C_L V_{DD}^2 \text{ En. totale dissipata}$$

Pot. dissipata:

$$P = f E_T = f C_L V_{DD}^2$$

Inoltre:

Passaggio di corrente nell'inverter durante le transizioni



Pot. dissipata

$$P_{SC} \simeq V_{DD} I_{max} \frac{t_{sal} + t_{disc}}{2} f$$

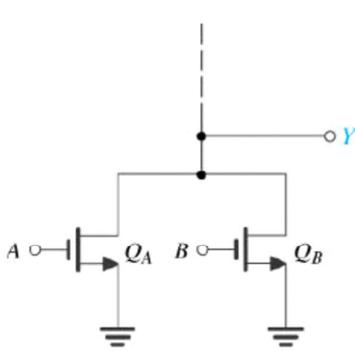
Inoltre:

Piccola potenza dissipata staticamente (correnti residue)

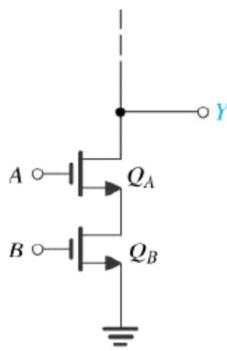
Totale:

$$P_{tot} = f C_L V_{DD}^2 + V_{DD} I_{max} \frac{t_{sal} + t_{disc}}{2} f + P_{stat}$$

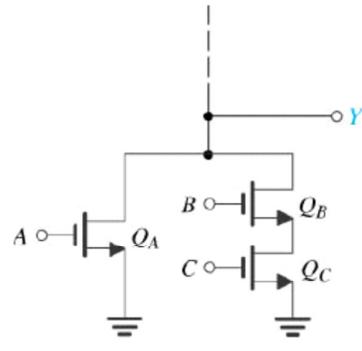
Esempi di reti logiche CMOS:



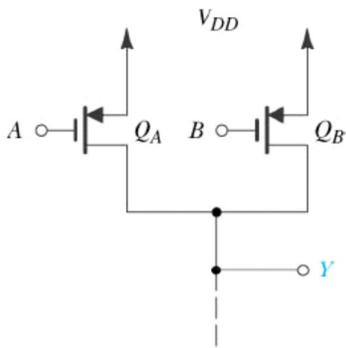
$$\bar{Y} = A + B$$



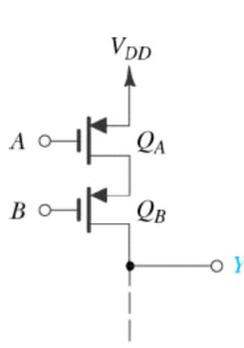
$$\bar{Y} = AB$$



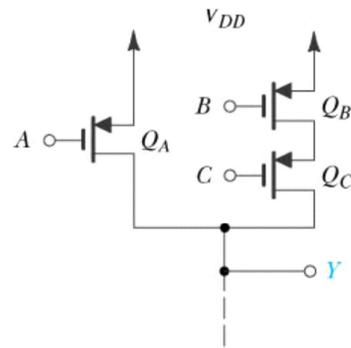
$$\bar{Y} = A + BC$$



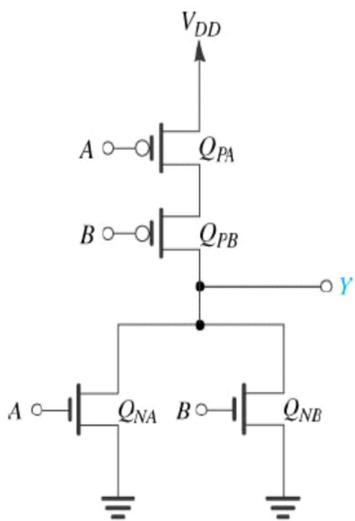
$$Y = \bar{A} + \bar{B}$$



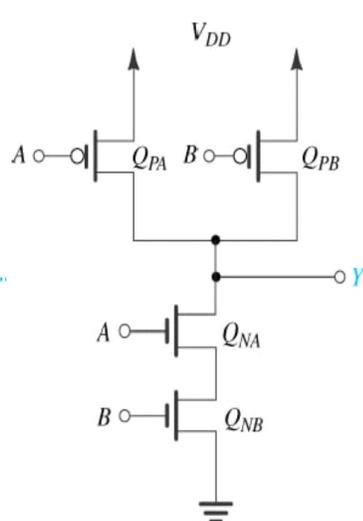
$$Y = \bar{A} \bar{B}$$



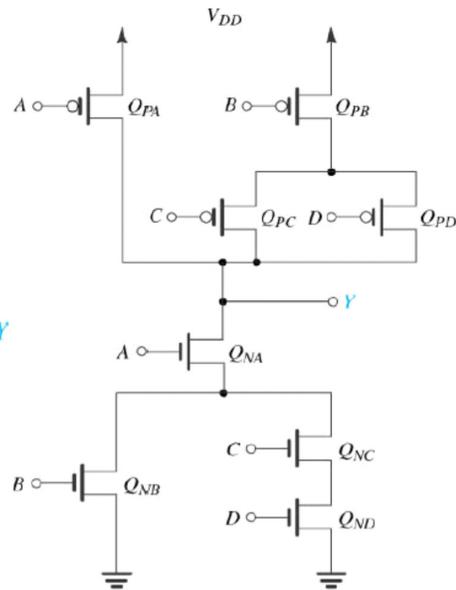
$$Y = \bar{A} + \bar{B} \bar{C}$$



$$Y = \bar{A} + B$$



$$Y = \bar{A} B$$



$$Y = \bar{A}(B + CD)$$